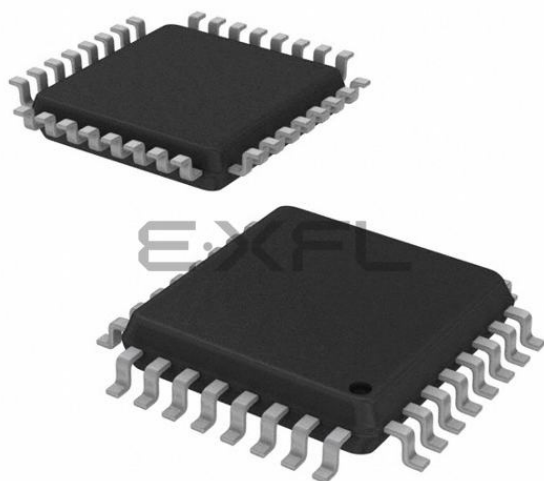




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Details

Product Status	Not For New Designs
Core Processor	STM8
Core Size	8-Bit
Speed	16MHz
Connectivity	I ² C, IrDA, LINbus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, DMA, POR, PWM, WDT
Number of I/O	29
Program Memory Size	16KB (16K x 8)
Program Memory Type	FLASH
EEPROM Size	1K x 8
RAM Size	2K x 8
Voltage - Supply (Vcc/Vdd)	1.65V ~ 3.6V
Data Converters	A/D 21x12b; D/A 1x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	32-LQFP
Supplier Device Package	32-LQFP (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm8al3l46tcy

- Development support
 - Fast on-chip programming and non intrusive debugging with SWIM
 - Bootloader using USART
- 96-bit unique ID

Table 1. Device summary

Reference	Part number
STM8AL313x/4x/6x (without LCD)	STM8AL3136, STM8AL3138, STM8AL3146, STM8AL3148, STM8AL3166, STM8AL3168
STM8AL3L4x/6x (with LCD)	STM8AL3L46, STM8AL3L48, STM8AL3L66, STM8AL3L68

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1 Introduction

This document describes the features, pinout, mechanical data and ordering information of the medium-density STM8AL313x/4x/6x and STM8AL3L4x/6x devices (microcontrollers with up to 32-Kbyte Flash memory density). These devices are referred to as medium-density devices in STM8L051/L052 Value Line, STM8L151/L152, STM8L162, STM8AL31, STM8AL3L MCU lines reference manual (RM0031) and in STM8L and STM8AL Flash programming manual (PM0054).

For more details on the whole STMicroelectronics ultra-low-power family please refer to [Section 3: Functional overview on page 13](#).

For information on the debug module and SWIM (single wire interface module), refer to the STM8 SWIM communication protocol and debug module user manual (UM0470).

For information on the STM8 core, please refer to the STM8 CPU programming manual (PM0044).

Note: The medium-density devices provide the following benefits:

- Integrated system
 - Up to 32 Kbytes of medium-density embedded Flash program memory
 - 1 Kbytes of data EEPROM
 - Internal high speed and low-power low speed RC.
 - Embedded reset
- Ultra-low power consumption
 - 195 μ A/MHZ + 440 μ A (consumption)
 - 0.9 μ A with LSI in Active-halt mode
 - Clock gated system and optimized power management
 - Capability to execute from RAM for Low power wait mode and Low power run mode
- Advanced features
 - Up to 16 MIPS at 16 MHz CPU clock frequency
 - Direct memory access (DMA) for memory-to-memory or peripheral-to-memory access.
- Short development cycles
 - Application scalability across a common family product architecture with compatible pinout, memory map and modular peripherals.
 - Wide choice of development tools

All devices offer 12-bit ADC, DAC, two comparators, Real-time clock three 16-bit timers, one 8-bit timer as well as standard communication interface such as SPI, I2C and USART. A 4x28-segment LCD is available on the medium-density STM8AL3Lxx line. [Table 2: Medium-density STM8AL313x/4x/6x and STM8AL3L4x/6x low-power device features and peripheral counts](#) and [Section 3: Functional overview](#) give an overview of the complete range of peripherals proposed in this family.

[Figure 1](#) shows the general block diagram of the device family.

3.2 Central processing unit STM8

3.2.1 Advanced STM8 core

The 8-bit STM8 core is designed for code efficiency and performance with an Harvard architecture and a 3-stage pipeline.

It contains six internal registers which are directly addressable in each execution context, 20 addressing modes including indexed indirect and relative addressing, and 80 instructions.

Architecture and registers

- Harvard architecture
- 3-stage pipeline
- 32-bit wide program memory bus - single cycle fetching most instructions
- X and Y 16-bit index registers - enabling indexed addressing modes with or without offset and read-modify-write type data manipulations
- 8-bit accumulator
- 24-bit program counter - 16 Mbyte linear memory space
- 16-bit stack pointer - access to a 64 Kbyte level stack
- 8-bit condition code register - 7 condition flags for the result of the last instruction

Addressing

- 20 addressing modes
- Indexed indirect addressing mode for lookup tables located anywhere in the address space
- Stack pointer relative addressing mode for local variables and parameter passing

Instruction set

- 80 instructions with 2-byte average instruction size
- Standard data movement and logic/arithmetic functions
- 8-bit by 8-bit multiplication
- 16-bit by 8-bit and 16-bit by 16-bit division
- Bit manipulation
- Data transfer between stack and accumulator (push/pop) with direct stack access
- Data transfer using the X and Y registers or direct memory-to-memory transfers

3.2.2 Interrupt controller

The medium-density STM8AL313x/4x/6x and STM8AL3L4x/6x feature a nested vectored interrupt controller:

- Nested interrupts with 3 software priority levels
- 32 interrupt vectors with hardware priority
- Up to 40 external interrupt sources on 11 vectors
- Trap and reset interrupts

3.13 Timers

The medium-density STM8AL313x/4x/6x and STM8AL3L4x/6x devices contain one advanced control timer (TIM1), two 16-bit general purpose timers (TIM2 and TIM3) and one 8-bit basic timer (TIM4).

All the timers can be served by DMA1.

[Table 3](#) compares the features of the advanced control, general-purpose and basic timers.

Table 3. Timer feature comparison

Timer	Counter resolution	Counter type	Prescaler factor	DMA1 request generation	Capture/compare channels	Complementary outputs
TIM1	16-bit	up/down	Any integer from 1 to 65536	Yes	3 + 1	3
TIM2			Any power of 2 from 1 to 128		2	None
TIM3						
TIM4	8-bit	up	Any power of 2 from 1 to 32768		0	

3.13.1 TIM1 - 16-bit advanced control timer

This is a high-end timer designed for a wide range of control applications. With its complementary outputs, dead-time control and center-aligned PWM capability, the field of applications is extended to motor control, lighting and half-bridge driver.

- 16-bit up, down and up/down auto reload counter with 16-bit prescaler
- Three independent capture/compare channels (CAPCOM) configurable as input capture, output compare, PWM generation (edge and center aligned mode) and single pulse mode output.
- One additional capture/compare channel which is not connected to an external I/O
- Synchronization module to control the timer with external signals
- Break input to force timer outputs into a defined state
- Three complementary outputs with adjustable dead time
- Encoder mode
- Interrupt capability on various events (capture, compare, overflow, break, trigger)

3.13.2 16-bit general purpose timers

- 16-bit auto reload (AR) up/down-counter
- 7-bit prescaler adjustable to fixed power of 2 ratios (1...128)
- Two individually configurable capture/compare channels
- PWM mode
- Interrupt capability on various events (capture, compare, overflow, break, trigger)
- Synchronization with other timers or external signals (external clock, reset, trigger and enable)

Table 5. Medium-density STM8AL313x/4x/6x and STM8AL3L4x/6x pin description (continued)

Pin number			Pin name	Type	I/O level	Input			Output			Main function (after reset)	Default alternate function
LQFP48	VQFPN32	LQFP32				floating	wpu	Ext. interrupt	High sink/source	OD	PP		
38	26	26	PC1 ⁽⁵⁾ /I2C1_SCL	I/O	FT	<u>X</u>	-	X	-	T ⁽⁷⁾		Port C1	I2C1 clock
41	27	27	PC2/USART1_RX/ LCD_SEG22/ADC1_IN6/ COMP1_INP/REFINT	I/O	TT ⁽³⁾	<u>X</u>	X	X	HS	X	X	Port C2	USART1 receive / LCD segment 22 / ADC1_IN6 / Comparator 1 positive input / Internal voltage reference output
42	28	28	PC3/USART1_TX/ LCD_SEG23 ⁽²⁾ / ADC1_IN5/COMP1_INP/ COMP2_INM	I/O	TT ⁽³⁾	<u>X</u>	X	X	HS	X	X	Port C3	USART1 transmit / LCD segment 23 / ADC1_IN5 / Comparator 1 positive input / Comparator 2 negative input
43	29	29	PC4/USART1_CK/ I2C1_SMB/CCO/ LCD_SEG24 ⁽²⁾ / ADC1_IN4/COMP2_INM/ COMP1_INP	I/O	TT ⁽³⁾	<u>X</u>	X	X	HS	X	X	Port C4	USART1 synchronous clock / I2C1_SMB / Configurable clock output / LCD segment 24 / ADC1_IN4 / Comparator 2 negative input / Comparator 1 positive input
44	30	30	PC5/OSC32_IN /[SPI1_NSS] ⁽⁴⁾ / [USART1_TX] ⁽⁴⁾	I/O	-	<u>X</u>	X	X	HS	X	X	Port C5	LSE oscillator input / [SPI1 master/slave select] / [USART1 transmit]
45	31	31	PC6/OSC32_OUT/ [SPI1_SCK] ⁽⁴⁾ / [USART1_RX] ⁽⁴⁾	I/O	-	<u>X</u>	X	X	HS	X	X	Port C6	LSE oscillator output / [SPI1 clock] / [USART1 receive]
46	-	-	PC7/LCD_SEG25 ⁽²⁾ / ADC1_IN3/COMP2_INM/ COMP1_INP	I/O	TT ⁽³⁾	<u>X</u>	X	X	HS	X	X	Port C7	LCD segment 25 /ADC1_IN3/ Comparator negative input / Comparator 1 positive input

Table 6. Flash and RAM boundary addresses

Memory area	Size	Start address	End address
RAM	2 Kbyte	0x00 0000	0x00 07FF
Flash program memory	8 Kbyte	0x00 8000	0x00 9FFF
	16 Kbyte		0x00 BFFF
	32 Kbyte		

5.2 Register map

Table 7. Factory conversion registers

Address	Block	Register label	Register name	Reset status
0x00 4910	-	VREFINT_Factory_CONV ⁽¹⁾	Internal reference voltage factory conversion	0xXX
0x00 4911	-	TS_Factory_CONV_V125 ⁽²⁾	Temperature sensor output voltage	0xXX

1. The VREFINT_Factory_CONV byte represents the 8 LSB of the result of the VREFINT 12-bit ADC conversion performed in factory. The MSB have a fixed value: 0x6.
2. The TS_Factory_CONV_V125 byte represents the 8 LSB of the result of the V125 12-bit ADC conversion performed in factory. The 2 MSB have a fixed value: 0x3.

Table 8. I/O port hardware register map

Address	Block	Register label	Register name	Reset status
0x00 5000	Port A	PA_ODR	Port A data output latch register	0x00
0x00 5001		PA_IDR	Port A input pin value register	0xXX
0x00 5002		PA_DDR	Port A data direction register	0x00
0x00 5003		PA_CR1	Port A control register 1	0x01
0x00 5004		PA_CR2	Port A control register 2	0x00
0x00 5005	Port B	PB_ODR	Port B data output latch register	0x00
0x00 5006		PB_IDR	Port B input pin value register	0xXX
0x00 5007		PB_DDR	Port B data direction register	0x00
0x00 5008		PB_CR1	Port B control register 1	0x00
0x00 5009		PB_CR2	Port B control register 2	0x00
0x00 500A	Port C	PC_ODR	Port C data output latch register	0x00
0x00 500B		PB_IDR	Port C input pin value register	0xXX
0x00 500C		PC_DDR	Port C data direction register	0x00
0x00 500D		PC_CR1	Port C control register 1	0x00
0x00 500E		PC_CR2	Port C control register 2	0x00

Table 9. General hardware register map (continued)

Address	Block	Register label	Register name	Reset status
0x00 507F	DMA1	DMA1_C1CR	DMA1 channel 1 configuration register	0x00
0x00 5080		DMA1_C1SPR	DMA1 channel 1 status & priority register	0x00
0x00 5081		DMA1_C1NDTR	DMA1 number of data to transfer register (channel 1)	0x00
0x00 5082		DMA1_C1PARH	DMA1 peripheral address high register (channel 1)	0x52
0x00 5083		DMA1_C1PARL	DMA1 peripheral address low register (channel 1)	0x00
0x00 5084		Reserved area (1 byte)		
0x00 5085		DMA1_C1M0ARH	DMA1 memory 0 address high register (channel 1)	0x00
0x00 5086		DMA1_C1M0ARL	DMA1 memory 0 address low register (channel 1)	0x00
0x00 5087 0x00 5088		Reserved area (2 bytes)		
0x00 5089		DMA1_C2CR	DMA1 channel 2 configuration register	0x00
0x00 508A		DMA1_C2SPR	DMA1 channel 2 status & priority register	0x00
0x00 508B		DMA1_C2NDTR	DMA1 number of data to transfer register (channel 2)	0x00

Table 9. General hardware register map (continued)

Address	Block	Register label	Register name	Reset status
0x00 540C	LCD	LCD_RAM0	LCD display memory 0	0x00
0x00 540D		LCD_RAM1	LCD display memory 1	0x00
0x00 540E		LCD_RAM2	LCD display memory 2	0x00
0x00 540F		LCD_RAM3	LCD display memory 3	0x00
0x00 5410		LCD_RAM4	LCD display memory 4	0x00
0x00 5411		LCD_RAM5	LCD display memory 5	0x00
0x00 5412		LCD_RAM6	LCD display memory 6	0x00
0x00 5413		LCD_RAM7	LCD display memory 7	0x00
0x00 5414		LCD_RAM8	LCD display memory 8	0x00
0x00 5415		LCD_RAM9	LCD display memory 9	0x00
0x00 5416		LCD_RAM10	LCD display memory 10	0x00
0x00 5417		LCD_RAM11	LCD display memory 11	0x00
0x00 5418		LCD_RAM12	LCD display memory 12	0x00
0x00 5419		LCD_RAM13	LCD display memory 13	0x00
0x00 541A to 0x00 542F	Reserved area (22 bytes)			
0x00 5430	RI	Reserved area (1 byte)		0x00
0x00 5431		RI_ICR1	Timer input capture routing register 1	0x00
0x00 5432		RI_ICR2	Timer input capture routing register 2	0x00
0x00 5433		RI_IOIR1	I/O input register 1	undefined
0x00 5434		RI_IOIR2	I/O input register 2	undefined
0x00 5435		RI_IOIR3	I/O input register 3	undefined
0x00 5436		RI_IOC MR1	I/O control mode register 1	0x00
0x00 5437		RI_IOC MR2	I/O control mode register 2	0x00
0x00 5438		RI_IOC MR3	I/O control mode register 3	0x00
0x00 5439		RI_IOSR1	I/O switch register 1	0x00
0x00 543A		RI_IOSR2	I/O switch register 2	0x00
0x00 543B		RI_IOSR3	I/O switch register 3	0x00
0x00 543C		RI_IOGCR	I/O group control register	0x3F
0x00 543D		RI_ASCR1	Analog switch register 1	0x00
0x00 543E		RI_ASCR2	Analog switch register 2	0x00
0x00 543F		RI_RCR	Resistor control register 1	0x00

8 Unique ID

The devices feature a 96-bit unique device identifier which provides a reference number that is unique for any device and in any context. The 96 bits of the identifier can never be altered by the user.

The unique device identifier can be read in single bytes and may then be concatenated using a custom algorithm.

The unique device identifier is ideally suited:

- For use as serial numbers
- For use as security keys to increase the code security in the program memory while using and combining this unique ID with software cryptographic primitives and protocols before programming the internal memory.
- To activate secure boot processes

Table 14. Unique ID registers (96 bits)

Address	Content description	Unique ID bits							
		7	6	5	4	3	2	1	0
0x4926	X co-ordinate on the wafer	U_ID[7:0]							
0x4927		U_ID[15:8]							
0x4928	Y co-ordinate on the wafer	U_ID[23:16]							
0x4929		U_ID[31:24]							
0x492A	Wafer number	U_ID[39:32]							
0x492B	Lot number	U_ID[47:40]							
0x492C		U_ID[55:48]							
0x492D		U_ID[63:56]							
0x492E		U_ID[71:64]							
0x492F		U_ID[79:72]							
0x4930		U_ID[87:80]							
0x4931		U_ID[95:88]							

Table 29. Current consumption under external reset

Symbol	Parameter	Conditions		Typ	Unit
I _{DD(RST)}	Supply current under external reset ⁽¹⁾	All pins are externally tied to V _{DD}	V _{DD} = 1.8 V	48	μA
			V _{DD} = 3 V	76	
			V _{DD} = 3.6 V	91	

1. All pins except PA0, PB0 and PB4 are floating under reset. PA0, PB0 and PB4 are configured with pull-up under reset.

9.3.4 Clock and timing characteristics

HSE external clock (HSEBYP = 1 in CLK_ECKCR)

Subject to general operating conditions for V_{DD} and T_A .

Table 30. HSE external clock characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{HSE_ext}	External clock source frequency	-	1 ⁽¹⁾	-	16 ⁽¹⁾	MHz
V_{HSEH}	OSC_IN input pin high level voltage		$0.7 \times V_{DD}$	-	V_{DD}	V
V_{HSEL}	OSC_IN input pin low level voltage		V_{SS}	-	$0.3 \times V_{DD}$	
$C_{in(HSE)}$	OSC_IN input capacitance	-	-	2.6	-	pF
I_{LEAK_HSE}	OSC_IN input leakage current	$V_{SS} < V_{IN} < V_{DD}$	-	-	± 500	nA

1. Guaranteed by design.

LSE external clock (LSEBYP=1 in CLK_ECKCR)

Subject to general operating conditions for V_{DD} and T_A .

Table 31. LSE external clock characteristics

Symbol	Parameter	Min	Typ	Max	Unit
f_{LSE_ext}	External clock source frequency	-	32.768	-	kHz
V_{LSEH}	OSC32_IN input pin high level voltage	$0.7 \times V_{DD}$ ⁽¹⁾	-	V_{DD} ⁽¹⁾	V
V_{LSEL}	OSC32_IN input pin low level voltage	V_{SS} ⁽¹⁾	-	$0.3 \times V_{DD}$ ⁽¹⁾	
$C_{in(LSE)}$	OSC32_IN input capacitance	-	0.6	-	pF
I_{LEAK_LSE}	OSC32_IN input leakage current	-		± 500	nA

1. Guaranteed by characterization results.

Table 40. I/O current injection susceptibility

Symbol	Description	Functional susceptibility		Unit
		Negative injection	Positive injection	
I _{INJ}	Injected current on true open-drain pins (PC0 and PC1)	-5	+0	mA
	Injected current on all five-volt tolerant (FT) pins	-5	+0	
	Injected current on all 3.6 V tolerant (TT) pins	-5	+0	
	Injected current on any other pin	-5	+5	

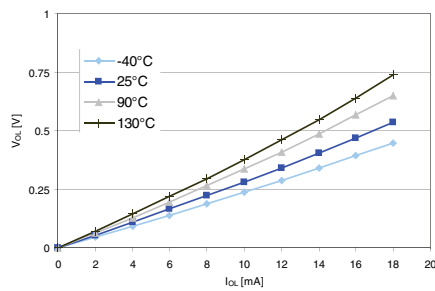
9.3.7 I/O port pin characteristics

General characteristics

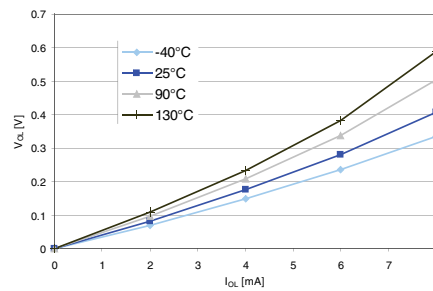
Subject to general operating conditions for V_{DD} and T_A unless otherwise specified. All unused pins must be kept at a fixed voltage: using the output mode of the I/O for example or an external pull-up or pull-down resistor.

Table 41. I/O static characteristics

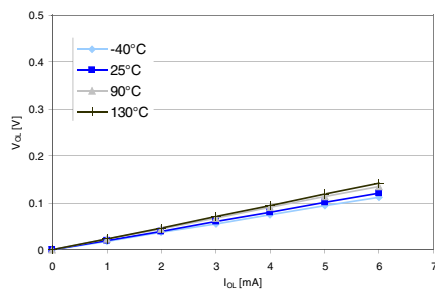
Symbol	Parameter	Conditions ⁽¹⁾	Min	Typ	Max	Unit
V _{IL}	Input low level voltage	Input voltage on all pins	$V_{SS}-0.3$	-	$0.3 \times V_{DD}$	V
V _{IH}	Input high level voltage	Input voltage on true open-drain pins (PC0 and PC1) with $V_{DD} < 2$ V	$0.70 \times V_{DD}$	-	5.2 ⁽²⁾	
		Input voltage on true open-drain pins (PC0 and PC1) with $V_{DD} \geq 2$ V		-	5.5 ⁽²⁾	
		Input voltage on five-volt tolerant (FT) pins (PA7 and PE0) with $V_{DD} < 2$ V	$0.70 \times V_{DD}$	-	5.2 ⁽²⁾	
		Input voltage on five-volt tolerant (FT) pins (PA7 and PE0) with $V_{DD} \geq 2$ V		-	5.5 ⁽²⁾	
		Input voltage on 3.6 V tolerant (TT) pins		-	3.6 ⁽²⁾	
		Input voltage on any other pin	$0.70 \times V_{DD}$	-	$V_{DD}+0.3$ ⁽²⁾	
V _{hys}	Schmitt trigger voltage hysteresis ⁽³⁾	I/Os	-	200	-	mV
		True open drain I/Os	-	200	-	
I _{lkg}	Input leakage current ⁽⁴⁾	$V_{SS} \leq V_{IN} \leq V_{DD}$ High sink I/Os	-	-	50	nA
		$V_{SS} \leq V_{IN} \leq V_{DD}$ True open drain I/Os	-	-	200	
		$V_{SS} \leq V_{IN} \leq V_{DD}$ PA0 with high sink LED driver capability	-	-	200	

Figure 23. Typ. V_{OL} @ $V_{DD} = 3.0$ V (high sink ports)

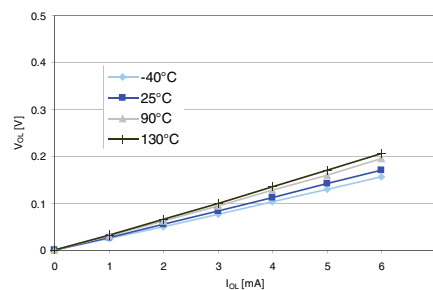
ai18226

Figure 24. Typ. V_{OL} @ $V_{DD} = 1.8$ V (high sink ports)

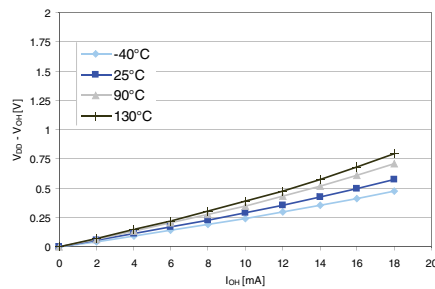
ai18227

Figure 25. Typ. V_{OL} @ $V_{DD} = 3.0$ V (true open drain ports)

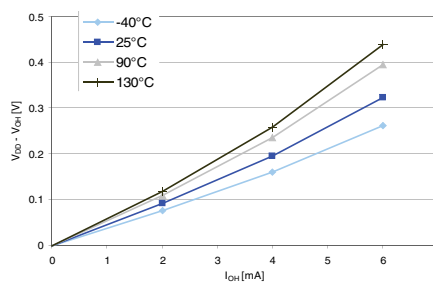
ai18228

Figure 26. Typ. V_{OL} @ $V_{DD} = 1.8$ V (true open drain ports)

ai18229

Figure 27. Typ. $V_{DD} - V_{OH}$ @ $V_{DD} = 3.0$ V (high sink ports)

ai12830

Figure 28. Typ. $V_{DD} - V_{OH}$ @ $V_{DD} = 1.8$ V (high sink ports)

ai18231

Table 50. TS characteristics (continued)

Symbol	Parameter	Min	Typ	Max.	Unit
$T_{START}^{(3)}$	Temperature sensor startup time	-	-	$10^{(2)}$	μs
T_{S_TEMP}	ADC sampling time when reading the temperature sensor	-	5	$10^{(2)}$	

1. Tested in production at $V_{DD} = 3\text{ V} \pm 10\text{ mV}$. The 8 LSB of the V_{125} ADC conversion result are stored in the $TS_Factory_CONV_V125$ byte.

2. Guaranteed by design.

3. Defined for ADC output reaching its final value $\pm 1/2\text{LSB}$.

9.3.12 Comparator characteristics

In the following table, data are guaranteed by design, not tested in production, unless otherwise specified.

Table 51. Comparator 1 characteristics

Symbol	Parameter	Min	Typ	Max	Unit
V_{DDA}	Analog supply voltage	1.65	-	$3.6^{(1)}$	V
T_A	Temperature range	-40	-	$125^{(1)}$	$^{\circ}\text{C}$
R_{400K}	R_{400K} value	300	400	$500^{(1)}$	$k\Omega$
R_{10K}	R_{10K} value	7.5	10	$12.5^{(1)}$	
V_{IN}	Comparator input voltage range	0.6	-	$V_{DDA}^{(1)}$	V
V_{REFINT}	Internal reference voltage	1.202	1.224	1.242	
t_{START}	Startup time after enable	-	7	$10^{(1)}$	μs
t_d	Propagation delay ⁽²⁾	-	3	$10^{(1)}$	
V_{offset}	Comparator offset error	-	± 3	$\pm 10^{(1)}$	mV
I_{CMP1}	Consumption ⁽³⁾	-	160	$260^{(1)}$	nA

1. Guaranteed by characterization results.

2. The delay is characterized for 100 mV input step with 10 mV overdrive on the inverting input, the non-inverting input set to the reference.

3. Comparator consumption only. Internal reference voltage not included.

In the following table, data are guaranteed by design, not tested in production unless otherwise specified.

Table 52. Comparator 2 characteristics

Symbol	Parameter	Conditions	Min	Typ	Max ⁽¹⁾	Unit
V_{DDA}	Analog supply voltage	-	1.65	-	3.6	V
T_A	Temperature range	-	-40	-	125	°C
V_{IN}	Comparator 2 input voltage range	-	0	-	V_{DDA}	V
t_{START}	Comparator startup time	Fast mode	-	15	20	μs
		Slow mode	-	20	25	
$t_{d\ slow}$	Propagation delay in slow mode ⁽²⁾	$1.65\ V \leq V_{DDA} \leq 2.7\ V$	-	1.8	3.5	
		$2.7\ V \leq V_{DDA} \leq 3.6\ V$		2.5	6	
$t_{d\ fast}$	Propagation delay in fast mode ⁽²⁾	$1.65\ V \leq V_{DDA} \leq 2.7\ V$	-	0.8	2	
		$2.7\ V \leq V_{DDA} \leq 3.6\ V$		1.2	4	
V_{offset}	Comparator offset error	-	-	± 4	± 20	mV
I_{COMP2}	Current consumption ⁽³⁾	Fast mode	-	3.5	5	μA
		Slow mode		0.5	2	

1. Guaranteed by characterization results.

2. The delay is characterized for 100 mV input step with 10 mV overdrive on the inverting input, the non-inverting input set to the reference.

3. Comparator consumption only. Internal reference voltage not included.

9.3.13 12-bit DAC characteristics

In the following table, data are guaranteed by design, not tested in production.

Table 53. DAC characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{DDA}	Analog supply voltage	-	1.8	-	3.6	V
V_{REF+}	Reference supply voltage	-	1.8	-	V_{DDA}	

In the following three tables, data are guaranteed by characterization result, not tested in production.

Table 57. ADC1 accuracy with $V_{DDA} = 2.5\text{ V}$ to 3.3 V

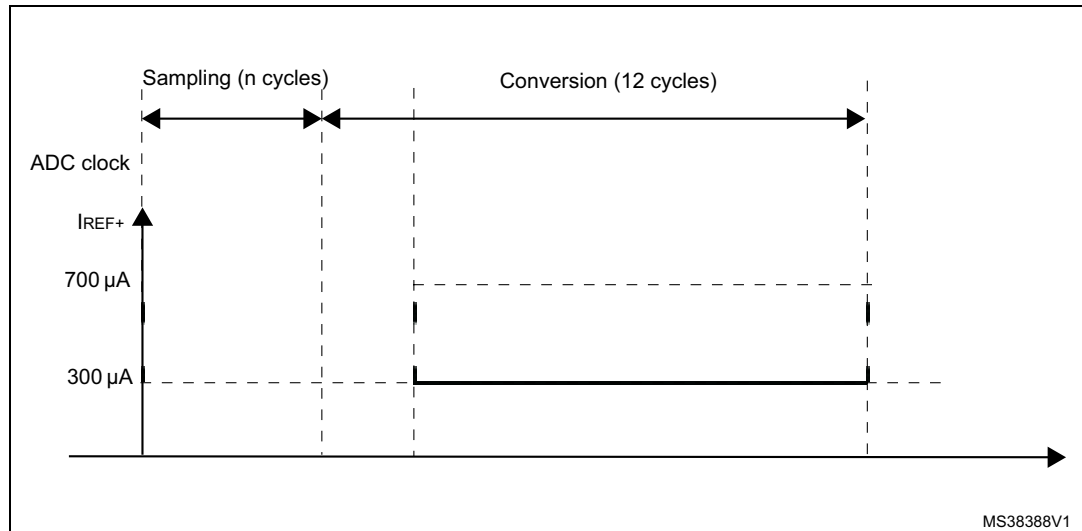
Symbol	Parameter	Conditions	Typ.	Max ⁽¹⁾	Unit
DNL	Differential non linearity	f _{ADC} = 16 MHz	1	1.6	LSB
		f _{ADC} = 8 MHz	1	1.6	
		f _{ADC} = 4 MHz	1	1.5	
INL	Integral non linearity	f _{ADC} = 16 MHz	1.2	2	
		f _{ADC} = 8 MHz	1.2	1.8	
		f _{ADC} = 4 MHz	1.2	1.7	
TUE	Total unadjusted error	f _{ADC} = 16 MHz	2.2	3.0	
		f _{ADC} = 8 MHz	1.8	2.5	
		f _{ADC} = 4 MHz	1.8	2.3	
Offset	Offset error	f _{ADC} = 16 MHz	1.5	2	LSB
		f _{ADC} = 8 MHz	1	1.5	
		f _{ADC} = 4 MHz	0.7	1.2	
Gain	Gain error	f _{ADC} = 16 MHz	1	1.5	
		f _{ADC} = 8 MHz			
		f _{ADC} = 4 MHz			

1. Not tested in production.

Table 58. ADC1 accuracy with $V_{DDA} = 2.4\text{ V}$ to 3.6 V

Symbol	Parameter	Typ.	Max ⁽¹⁾	Unit
DNL	Differential non linearity	1	2	LSB
INL	Integral non linearity	1.7	3	
TUE	Total unadjusted error	2	4	
Offset	Offset error	1	2	
Gain	Gain error	1.5	3	

1. Not tested in production.

Figure 38. Maximum dynamic current consumption on V_{REF+} supply pin during ADC conversion**Table 60. R_{AIN} max for $f_{ADC} = 16 \text{ MHz}^{(1)}$**

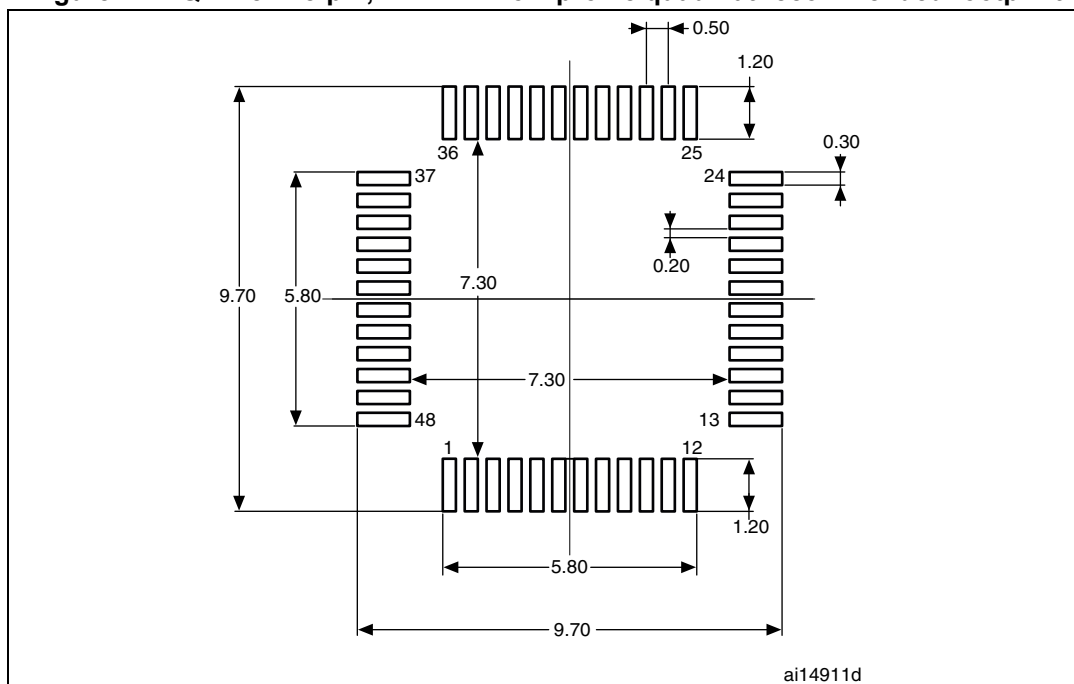
Ts (cycles)	Ts (µs)	R_{AIN} max (kohm)			
		Slow channels		Fast channels	
		$2.4 \text{ V} < V_{DDA} < 3.6 \text{ V}$	$1.8 \text{ V} < V_{DDA} < 2.4 \text{ V}$	$2.4 \text{ V} < V_{DDA} < 3.3 \text{ V}$	$1.8 \text{ V} < V_{DDA} < 2.4 \text{ V}$
4	0.25	Not allowed	Not allowed	0.7	Not allowed
9	0.5625	0.8	Not allowed	2.0	1.0
16	1	2.0	0.8	4.0	3.0
24	1.5	3.0	1.8	6.0	4.5
48	3	6.8	4.0	15.0	10.0
96	6	15.0	10.0	30.0	20.0
192	12	32.0	25.0	50.0	40.0
384	24	50.0	50.0	50.0	50.0

1. Guaranteed by design.

General PCB design guidelines

Power supply decoupling should be performed as shown in [Figure 39](#) or [Figure 40](#), depending on whether V_{REF+} is connected to V_{DDA} or not. Good quality ceramic 10 nF capacitors should be used. They should be placed as close as possible to the chip.

Figure 42. LQFP48 - 48-pin, 7 x 7 mm low-profile quad flat recommended footprint

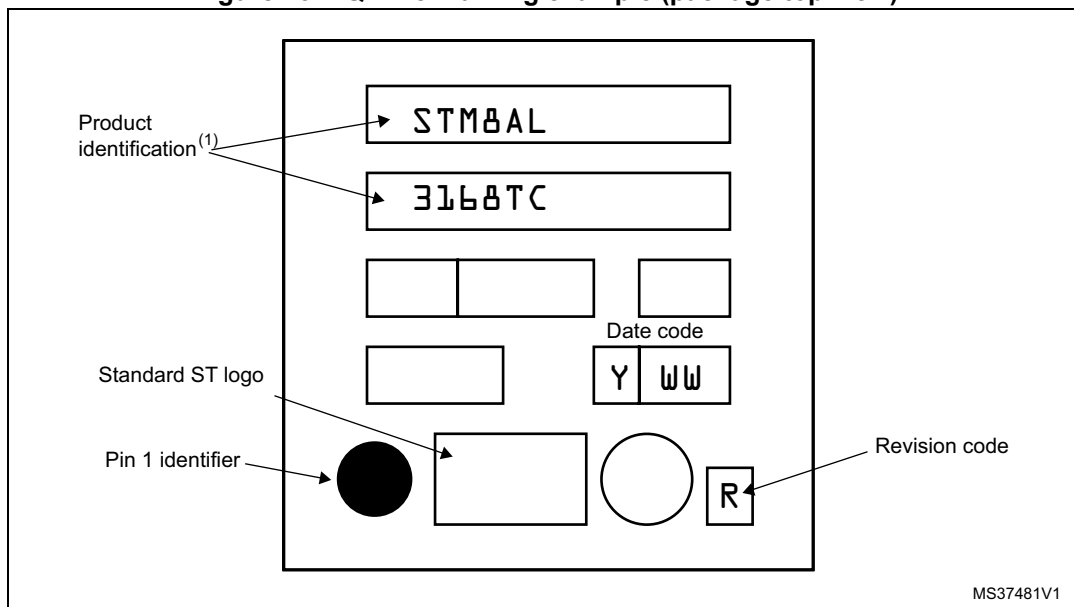


1. Dimensions are expressed in millimeters.

Device marking

The following figure gives an example of topside marking orientation versus pin 1 identifier location. Other optional marking or inset/upset marks, which identify the parts throughout supply chain operations, are not indicated below.

Figure 43. LQFP48 marking example (package top view)



1. Parts marked as "ES" or "E" are not yet qualified and therefore not approved for use in production. ST is not responsible for any consequences resulting from such use. In no event will ST be liable for the customer using any of these engineering samples in production. ST's Quality department must be contacted prior to any decision to use these engineering samples to run a qualification activity.